

# Search Notes



Application/Control No.

10/699,135

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

TOHSCHKE, ULF

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	202	06.07.04	Nh
	203	↓	↓
	206	↓	↓
	208	↓	↓
	218	↓	↓
327	197	06.14.05	Nh
All searches			
rechecked		06.14.05	Nh

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
327	197	06.14.05	Nh
	202	↓	↓
	203	↓	↓

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	06.07.04	Nh
EAST see attachment	06.14.05	Nh